

January 2001

Si9424DY

Single P-Channel 2.5V Specified PowerTrench MOSFET

General Description

This P-Channel 2.5V specified MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

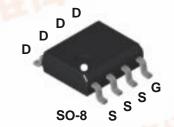
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

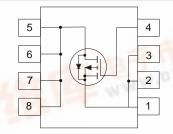
Applications

- DC/DC converter
- Load switch
- Battery Protection

Features

- -8.0 A, -20 V. $R_{DS(on)} = 0.024~\Omega~$ @ $V_{GS} = -4.5~V$ $R_{DS(on)} = 0.032~\Omega~$ @ $V_{GS} = -2.5~V.$
- Low gate charge (23nC typical).
- Fast switching speed.
- High performance trench technology for extremely low R_{DS(ON)}.
- High power and current handling capability.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V_{GSS}	Gate-Source Voltage		± 10	V
I _D	Drain Current - Continuous	(Note 1a)	-8.0	A
	- Pulsed		-50	Leg.
P _D	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
	-	(Note 1c)	1	
TJ, Tsta	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta^{JA}}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	∘C/W		
R _{OJC}	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W		

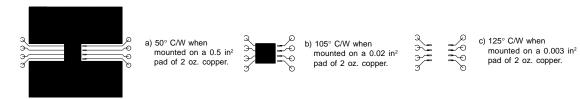
Package Outlines and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
9424	Si9424DY	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-20			V
∆BVdss ∆Tj	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-24		mV/°C
DSS	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μΑ
GSSF	Gate-Body Leakage Current, Forward	$V_{GS} = 10 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
GSSR	Gate-Body Leakage Current, Reverse	V _{GS} = -10 V, V _{DS} = 0 V			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.4	-0.8	-1.5	V
ΔVGS(th)	Gate Threshold Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		5		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -8 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -8 \text{ A}, T_J = 125 ^{\circ}\text{C}$ $V_{GS} = -2.5 \text{ V}, I_D = -7 \text{ A}$		0.019 0.026 0.027	0.024 0.039 0.032	Ω
D(on)	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5.0 \text{ V}$	-50			Α
g _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -8 \text{ A}$		28		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$		2260		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		500		pF
Crss	Reverse Transfer Capacitance			205		pF
Switchin	g Characteristics (Note 2)			I	1	-
d(on)	Turn-On Delay Time	$V_{DD} = -10 \text{ V}, I_D = -1 \text{ A},$		8	16	ns
r	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		15	27	ns
d(off)	Turn-Off Delay Time			98	135	ns
f	Turn-Off Fall Time			35	55	ns
Q_g	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -8 \text{ A},$		23	33	nC
Q_{gs}	Gate-Source Charge	$V_{GS} = -5 V$,		5.5		nC
<u>ુુુ</u> ગુવ	Gate-Drain Charge			4		nC
	urco Diodo Characteristics an	d Maximum Patings			<u>. </u>	
s	urce Diode Characteristics and Maximum Continuous Drain-Source Did	_			-2.1	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = -2.1 A (Note 2)		-0.75	-1.2	V

Notes

1: R_{BJA} is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BJA} is determined by the user's board design.



Scale 1 : 1 on letter size paper

2: Pulse Test: Pulse Width $\leq 300~\mu s$, Duty Cycle $\leq 2.0\%$

Typical Characteristics

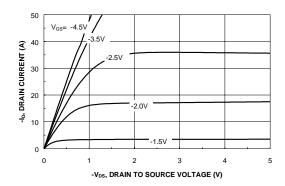


Figure 1. On-Region Characteristics.

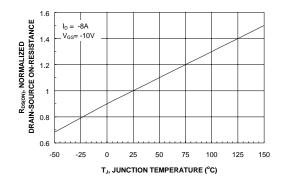


Figure 3. On-Resistance Variation with Temperature.

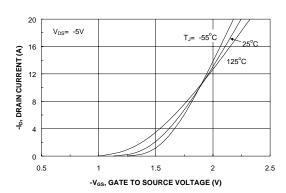


Figure 5. Transfer Characteristics.

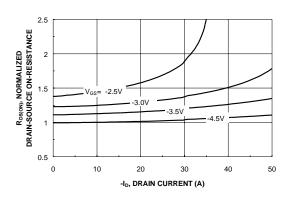


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

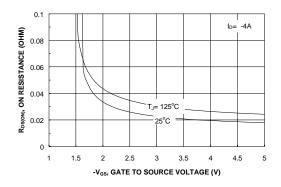


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

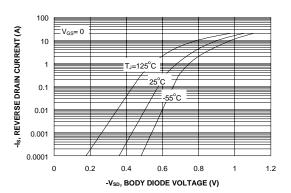
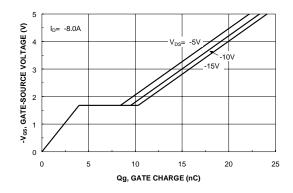


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



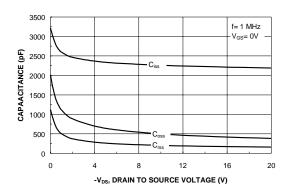
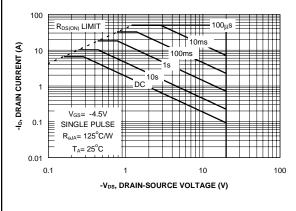


Figure 7. Gate Charge Characteristics.





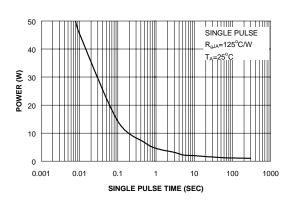


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

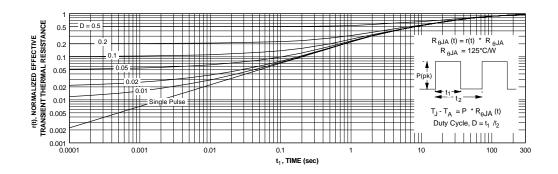


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient themal response will change depending on the circuit board design.

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